


<b>Search Notes</b>  	<b>Application/Control No.</b>  10589712	<b>Applicant(s)/Patent Under Reexamination</b>  LUCAS ET AL.
	<b>Examiner</b>  Phillip H Nguyen	<b>Art Unit</b>  2191

SEARCHED			
Class	Subclass	Date	Examiner
700	98	5/25/2010	PN
717	105	5/25/2010	PN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: search all databases (US_PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB); text search	5/25/2010	PN
PALM: inventor name search.	5/25/2010	PN
STIC: plus search.	5/25/2010	PN
Google Scholar text search.	5/25/2010	PN

INTERFERENCE SEARCH			
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